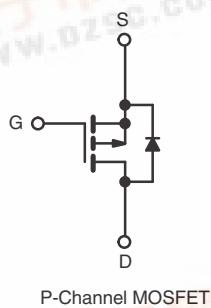
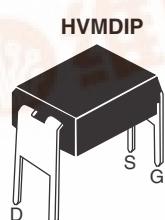


Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)		- 200
$R_{DS(on)}$ (Ω)	$V_{GS} = - 10$ V	1.5
Q_g (Max.) (nC)		15
Q_{gs} (nC)		3.2
Q_{gd} (nC)		8.4
Configuration		Single

RoHS*
COMPLIANT

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- For Automatic Insertion
- End Stackable
- P-Channel
- Fast Switching
- Ease of Parallelizing
- Compliant to RoHS Directive 2002/95/EC

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The 4 pin DIP package is a low cost machine-insertable case style which can be stacked in multiple combinations on standard 0.1" pin centers. The dual drain serves as a thermal link to the mounting surface for power dissipation levels up to 1 W.

ORDERING INFORMATION			
Package			HVMDIP
Lead (Pb)-free			IRFD9220PbF SiHFD9220-E3
SnPb			IRFD9220 SiHFD9220

ABSOLUTE MAXIMUM RATINGS ($T_A = 25$ °C, unless otherwise noted)				
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V_{DS}	- 200	V
Gate-Source Voltage		V_{GS}	± 20	
Continuous Drain Current	V_{GS} at - 10 V	I_D	- 0.56	A
			- 0.36	
Pulsed Drain Current ^a		I_{DM}	- 4.5	
Linear Derating Factor			0.0083	W/°C
Single Pulse Avalanche Energy ^b		E_{AS}	420	mJ
Avalanche Current ^a		I_{AR}	- 0.56	A
Repetitive Avalanche Energy ^a		E_{AR}	0.10	mJ
Maximum Power Dissipation	$T_A = 25$ °C	P_D	1.0	W
Peak Diode Recovery dV/dt ^c		dV/dt	- 5.0	V/ns
Operating Junction and Storage Temperature Range		T_J, T_{stg}	- 55 to + 150	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	°C

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = - 50$ V, starting $T_J = 25$ °C, $L = 130$ mH, $R_g = 25 \Omega$, $I_{AS} = - 2.2$ A (see fig. 12).
- $I_{SD} \leq - 3.9$ A, $dI/dt \leq 95$ A/ μ s, $V_{DD} \leq V_{DS}$, $T_J \leq 150$ °C.
- 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

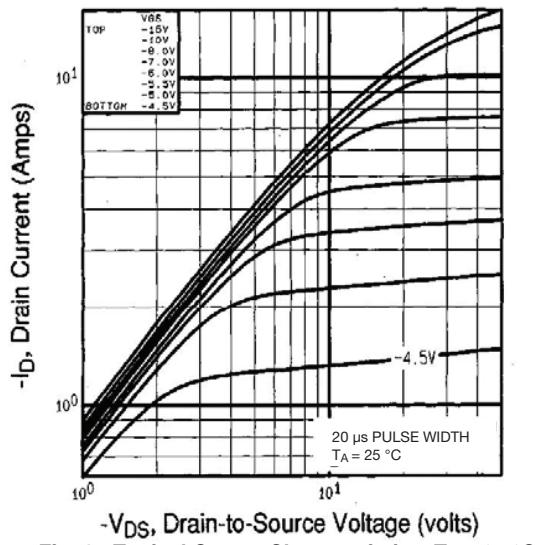
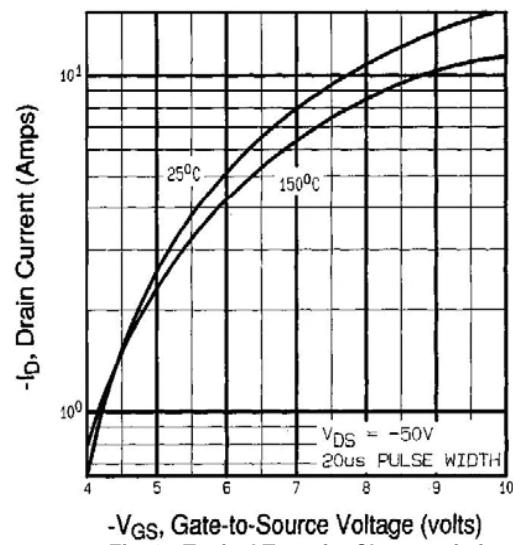
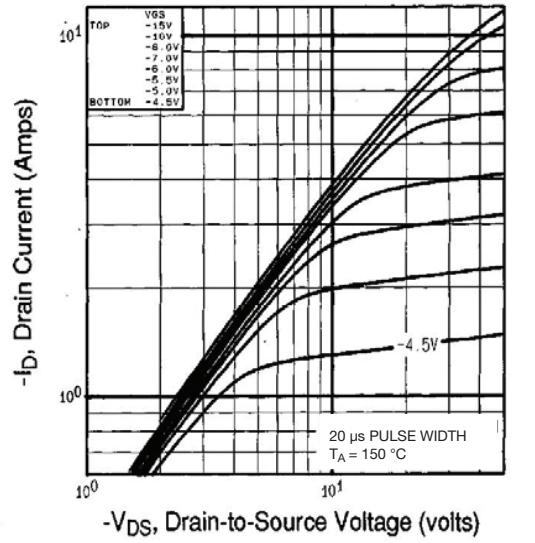
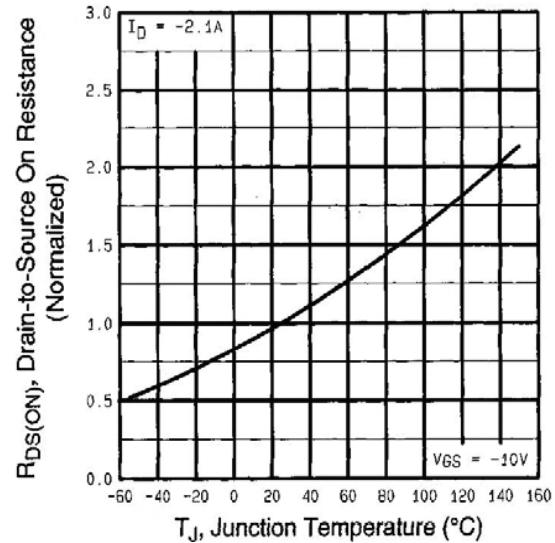
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	120	°C/W

SPECIFICATIONS ($T_J = 25^\circ\text{C}$, unless otherwise noted)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = -250 \mu\text{A}$		-200	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = -1 \text{ mA}$		-	-0.22	-	$\text{V}/^\circ\text{C}$
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$, $I_D = -250 \mu\text{A}$		-2.0	-	-4.0	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -200 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	-100	μA
		$V_{DS} = -160 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125^\circ\text{C}$		-	-	-500	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = -10 \text{ V}$	$I_D = -0.34 \text{ A}^b$	-	-	1.5	Ω
Forward Transconductance	g_{fs}	$V_{DS} = -50 \text{ V}$, $I_D = -0.35 \text{ A}^b$		0.55	-	-	S
Dynamic							
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = -25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	340	-	pF
Output Capacitance	C_{oss}			-	110	-	
Reverse Transfer Capacitance	C_{rss}			-	33	-	
Total Gate Charge	Q_g	$V_{GS} = -10 \text{ V}$	$I_D = -2.1 \text{ A}$, $V_{DS} = -160 \text{ V}$, see fig. 6 and 13 ^b	-	-	15	nC
Gate-Source Charge	Q_{gs}			-	-	3.2	
Gate-Drain Charge	Q_{gd}			-	-	8.4	
Turn-On Delay Time	$t_{d(on)}$			-	8.8	-	
Rise Time	t_r	$V_{DD} = -100 \text{ V}$, $I_D = -3.9 \text{ A}$, $R_g = 18 \Omega$, $R_D = 24 \Omega$, see fig. 10 ^b		-	27	-	ns
Turn-Off Delay Time	$t_{d(off)}$		-	7.3	-		
Fall Time	t_f		-	19	-		
Internal Drain Inductance	L_D		-	4.0	-	nH	
Internal Source Inductance	L_S	Between lead, 6 mm (0.25") from package and center of die contact		-	6.0		-
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	-0.56	A
Pulsed Diode Forward Current ^a	I_{SM}			-	-	-4.5	
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}$, $I_S = -0.56 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	-6.3	V
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}$, $I_F = -3.9 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	150	300	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	0.97	2.0	μC

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Fig. 1 - Typical Output Characteristics, T_A = 25 °C

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics, T_A = 150 °C

Fig. 4 - Normalized On-Resistance vs. Temperature

IRFD9220, SiHFD9220

Vishay Siliconix SiHFD9220"供应商

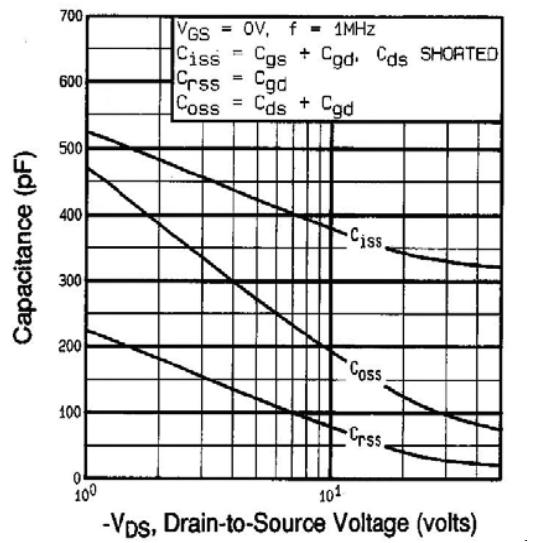


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

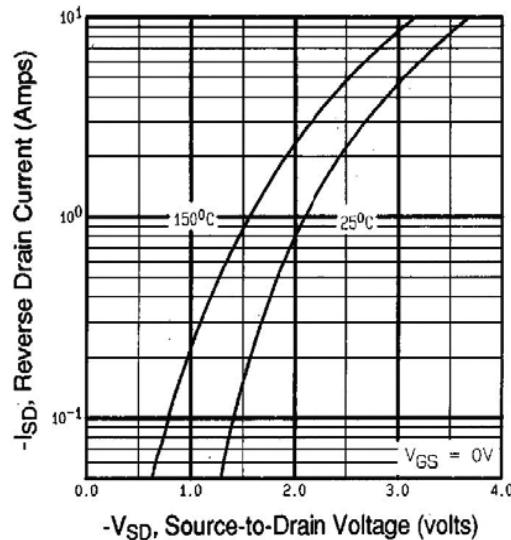


Fig. 7 - Typical Source-Drain Diode Forward Voltage

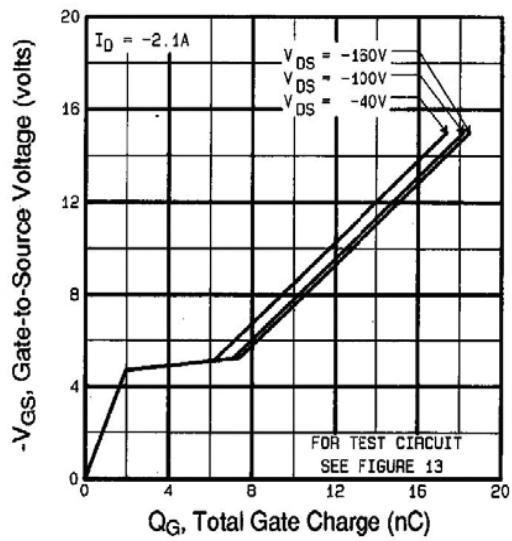


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

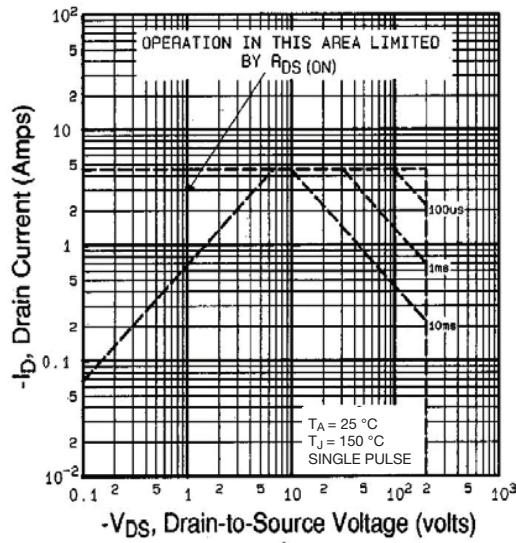


Fig. 8 - Maximum Safe Operating Area

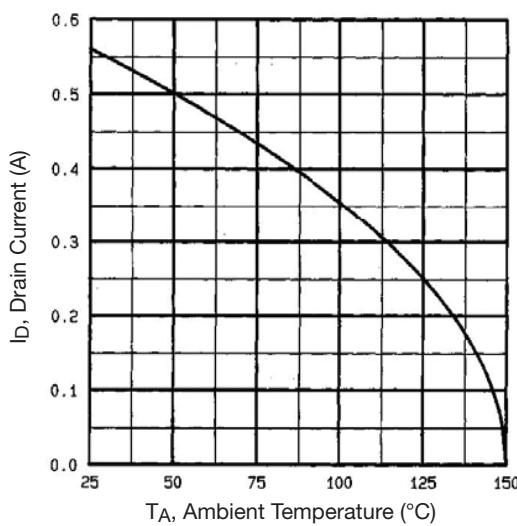


Fig. 9 - Maximum Drain Current vs. Ambient Temperature

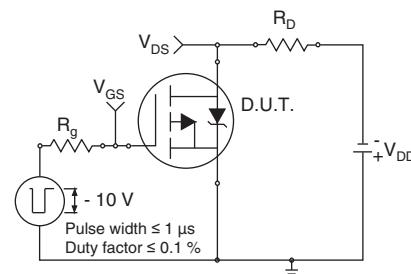


Fig. 10a - Switching Time Test Circuit

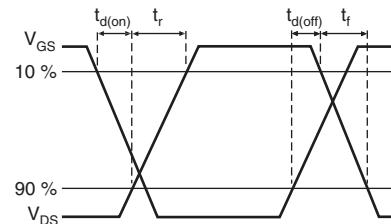


Fig. 10b - Switching Time Waveforms

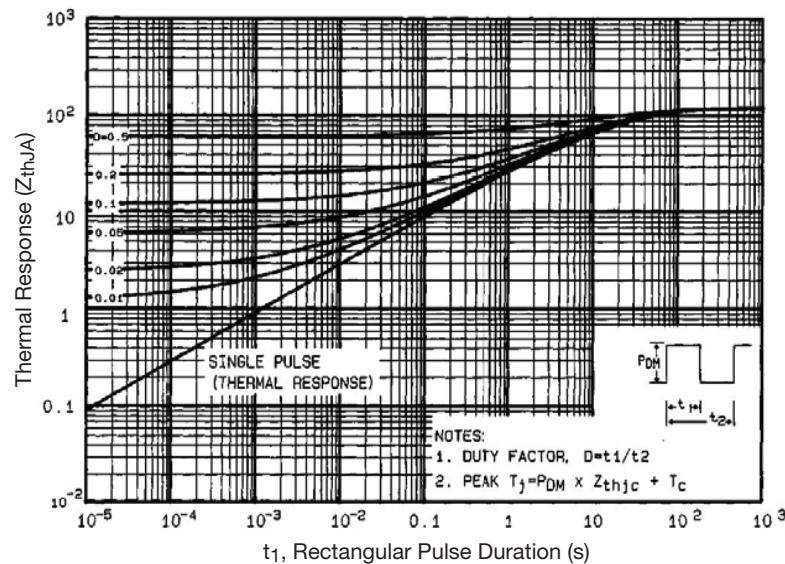


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

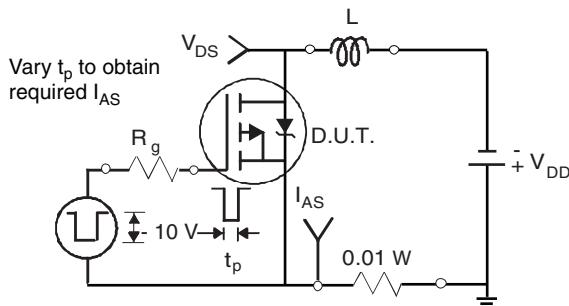


Fig. 12a - Unclamped Inductive Test Circuit

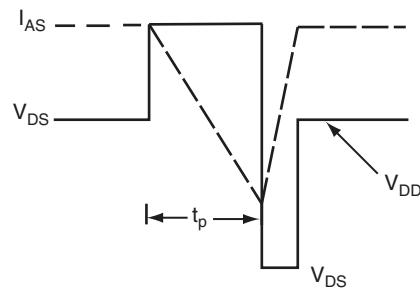


Fig. 12b - Unclamped Inductive Waveforms

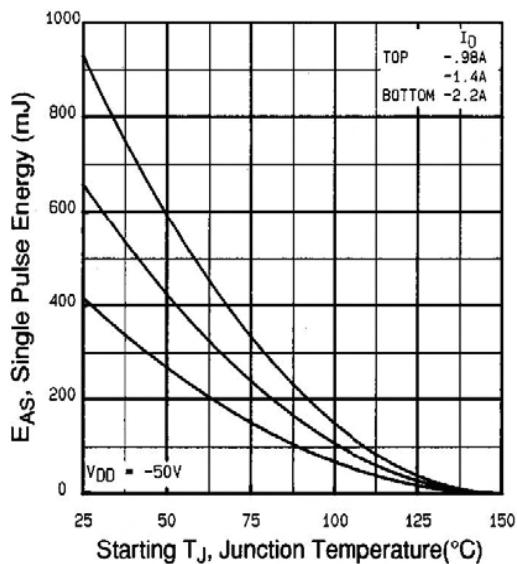


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

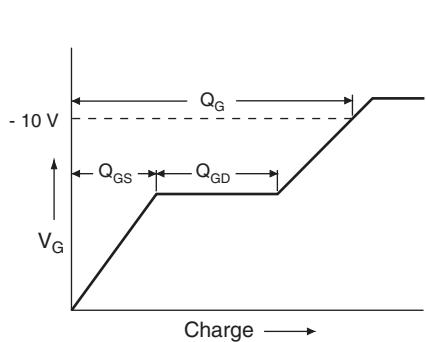


Fig. 13a - Basic Gate Charge Waveform

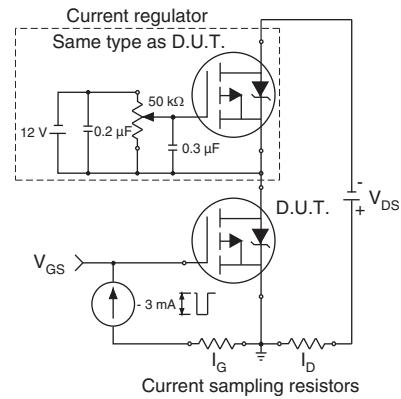
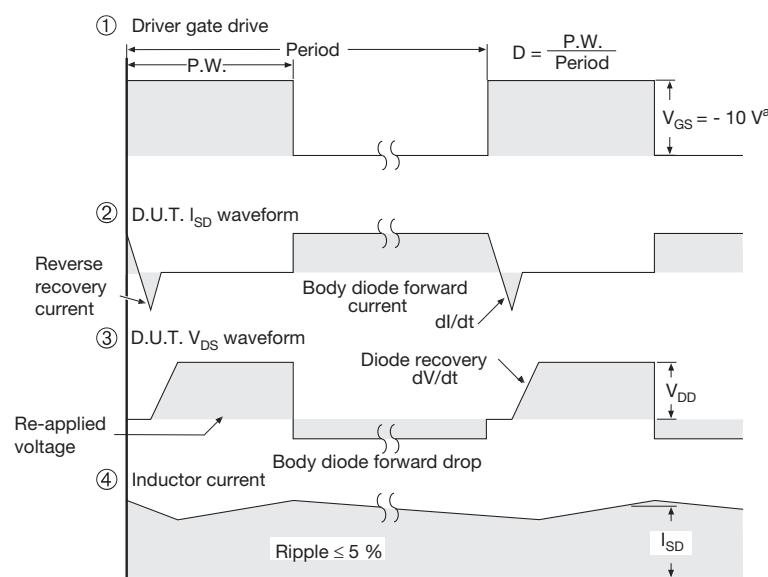
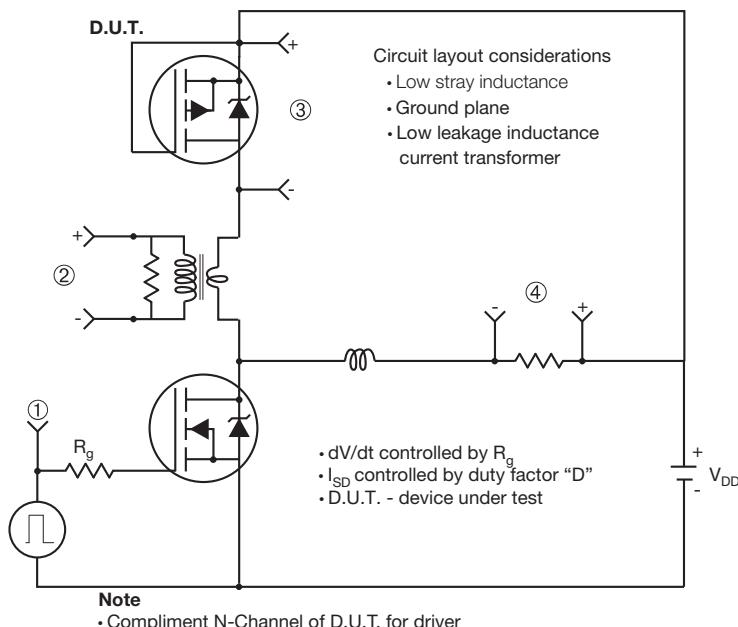


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit

Fig. 14 - For P-Channel

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